INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Not for submission under 37 CFR 1.99)

Application Number	10629302
Filing Date	2003-07-28
First Named Inventor	Lewis B. Aronson
Art Unit	2613
Examiner Name	Dzung D. Tran
Attorney Docket Number	15436.247.2.1.4

	U.S. PATENTS					
Examiner Initials*	Cite No.	Patent Number	Issue Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
/D.T./	1	4489477	1984-12-25	Chik et al		
/D.T./	2	6977517	2005-12-20	Miao et al		
/D.T./	3	7019548	2006-03-28	Miao et al		
/D.T./	4	7477847	2009-01-13	Hofmeister et al.		
/D.T./	5	6466886	2002-10-15	Marmur		

	U.S. PATENT APPLICATION PUBLICATIONS						
Examiner Initials*							
/D.T./	/D.T./ 1 20040076114 2004-04-22 Minello						

	FOREIGN PATENT DOCUMENTS						
Examiner Cite Foreign Patent Country Publication Date Name of Patentee or Applicant Where Relevant						Passages or Relevant	T 1
/D.T./	1	2005006575	wo	2005-01-20	Finisar Corp		
/D.T./	2	1503232	EP	2004-07-27	Emcore Corp		
/D.T./	3	2004135106	JP	2004-04-30	Hitachi Ltd		
/D.T./	4	224406	TW	2004-11-21	Hon Hai Prec Ind Co Ltd		
/D.T./	5	555297	TW	2003-09-21		Could not obtain copy	

	FOREIGN OFFICE ACTION / NOTICE OF ALLOWANCE DOCUMENTS				
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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published	T 1
/D.T./	1	HAWTHORNE: "850nm Proton VCSEL Reliability Study" Technical Publications and Application Notes, Advances Optical Components (Finisar Corp), Issue 2, September 2001, pgs 1-7, Richardson, TX	
/D.T./	2	MECHERLE G S ET AL: "Considerations for Accelerated Laser Diode Life Testing" Proceedings of the Spie, Spie, Bellingham, VA, vol. 717, 1986, pgs 53-62	
/D.T./	3	TEBBI O ET AL: "Comparitive study of acclerated testing models, applications in mechanics" 2001 IEEE International Conference on Systems Man and Cybernetics SMC 2001. Tucson, AZ Oct 7-10, 2001, IEEE International Conference on Systems, Man and Cybernetics, New York, NY: IEEE, US, vol 1 of 5 Oct 7, 2001 pgs 2099-2104	
/D.T./	4	J.D. BARRY ET AL: Thermally Accelerated Life Testing of Single Mode, Double-Heterostructure, AlGaAs Laser Diodes Operated Pulsed at 50 mW Peak Power' IEEE Journal of Quantum Electronics, vol. 21, no. 4 December 25, 1984 pgs 365-376	

	OFFICE ACTION / NOTICE OF ALLOWANCE DOCUMENTS				
Examiner Initials*	Cite No.	Application Number	Mail Date	Document	
/D.T./	1	11118172	2008-09-04	Office Action	
/D.T./	2	10629301	2008-04-01	Office Action	
/D.T./	3	11073452	2008-08-07	Office Action	
/D.T./	4	11118172	2008-03-25	Office Action	
/D.T./	5	11073452	2007-12-31	Office Action	
/D.T./	6	10629301	2008-11-26	Office Action	
/D.T./	7	10884334	2009-01-16	Office Action	
/D.T./	8	10884334	2008-07-10	Office Action	
/D.T./	9	10626965	2007-01-24	Office Action	
/D.T./	10	10626965	2007-08-09	Office Action	
/D.T./	11	10420027	2007-12-12	Office Action	
/D.T./	12	10629228	2008-01-03	Office Action	
/D.T./	13	10626965	2008-03-18	Office Action	
/D.T./	14	10697395	2008-05-30	Office Action	
/D.T./	15	10420027	2008-06-25	Office Action	
/D.T./	16	10884334	2008-01-31	Office Action	

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EXAMINER SIGNATURE					
Examiner Signature	/Dzung Tran/	Date Considered	06/21/2009		
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through					

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